

<p align="center">Notice of References Cited</p>	Application/Control No. 10/089,840	Applicant(s)/Patent Under Reexamination FUJISAWA ET AL.	
	Examiner Binh-An D. Nguyen	Art Unit 3713	Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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